2021

ELECTRONICS—GENERAL

Paper: DSE-A-1

(Semiconductor Devices Fabrication)

Full Marks: 50

The figures in the margin indicate full marks.

Candidates are required to give their answers in their own words as far as practicable.

Answer *Question No. 1* and *any four* from the rest.

1.	Answer any ten:				1×10
	(a)	Conductivity of metal with increasing	ng ter	nperature.	
		(i) increases	(ii)	decreases	
		(iii) remains invariant	(iv)	remains the same	
	(b)	Schottky defect is a defect.			
		(i) point	(ii)	line	
		(iii) volume	(iv)	None of these	
	(c)	For <i>n</i> type doping in Si is used.			
		(i) Al	(ii)	Ge	
		(iii) As	(iv)	In	
	(d)	Primary pump creates vacuum than secondary pumps.			
		(i) more	(ii)	less	
		(iii) same	(iv)	None of these	
	(e)	PLD is a vapour deposition techniqu	ie.		
		(i) chemical	(ii)	physical	
		(iii) structural	(iv)	fundamental	
	(f)	In epitaxial growth, the grown layer is	·		
		(i) amorphous	(ii)	polycrystalline	
		(iii) single crystalline	(iv)	None of these	
	(g)	The inter-solid diffusion can occur by two types of movements and			
		(i) substitutional, and interstitial	(ii)	substitutional, and combinational	
		(iii) combinational, and interstitial	(iv)	None of these	

(b) Why enhancement mode MOSFETs are 'naturally OFF' and depletion mode MOSFETs are 'normally

(c) Draw the transfer characteristics of an *n*-channel enhancement mode MOSFET and show the threshold

(3+4+3)

voltage in the characteristic curve. What is meant by threshold voltage?

ON' devices?

- 7. (a) Schematically explain the fabrication process of PN junction.
 - (b) Differentiate between bipolar technology and MOS technology.

(c) Why NMOS is preferred to PMOS?

(5+3+2)

- **8.** (a) Why material selection is important for MEMS devices?
 - (b) Differentiate between surface and bulk micromachining.
 - (c) Briefly discuss (i) sacrificial subtractive process and (ii) additive process.

 $2+3+(2\frac{1}{2}+2\frac{1}{2})$
